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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re United States Patent Application of:

Applicant: David S. Kurtz et al.

Serial No.: 09/884,791

Date Filed: June 19, 2001

**Title: METHOD AND APPARATUS FOR
RAPID GRAIN SIZE ANALYSIS OF
POLYCRYSTALLINE MATERIALS**

Docket No.: 4173-101

Examiner: Ryan J. MILLER

Art Group: 2621

Confirm. No.: 4360

23448

EXPRESS MAIL CERTIFICATE

I hereby certify that I am mailing the attached documents to the Commissioner for Patents on the date specified, in an envelope addressed to the Mail Stop Amendment, Commissioner for Patents, PO Box 1450, Alexandria, VA 22313-1450, and Express Mailed under the provisions of 37 CFR 1.10.

RECEIVED

AUG 05 2004

Technology Center 2600


L. Stephen Lockett

July 29, 2004
Date

EO 002 337 878 US
Express Mail Label Number

**RESPONSE TO JULY 1, 2004 OFFICE ACTION
IN U.S. PATENT APPLICATION NO. 09/884,791**

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313

Sir:

In response to the Office Action dated July 1, 2004 in the above-identified patent application, please amend the present application as in Section I (Amendments to the Specification), Section II (Amendments to Drawing Figures), and Section III (Amendments to the Claims) below.